

ANTIMONIDE-BASED INFRARED DETECTORS

A New Perspective

ANTIMONIDE-BASED INFRARED DETECTORS

A New Perspective

Antoni Rogalski, Małgorzata Kopytko, and Piotr Martyniuk

SPIE PRESS

Bellingham, Washington USA

Library of Congress Cataloging-in-Publication Data

Names: Rogalski, Antoni, author. | Kopytko, Małgorzata, author. | Martyniuk, Piotr, author.

Title: Antimonide-based infrared detectors : a new perspective / Antoni Rogalski, Małgorzata Kopytko, and Piotr Martyniuk.

Description: Bellingham, Washington, USA : SPIE Press, [2018] | Includes bibliographical references and index.

Identifiers: LCCN 2017013783 | ISBN 9781510611399 (print ; alk. paper) | ISBN 1510611398 (print ; alk. paper) | ISBN 9781510611405 (PDF) | ISBN 1510611401 (PDF) | ISBN 9781510611412 (ePub) | ISBN 151061141X (ePub) | ISBN 9781510611429 (Kindle/Mobi) | ISBN 1510611428 (Kindle/Mobi)

Subjects: LCSH: Infrared detectors. | Infrared technology Materials. | Semiconductors. | Antimonides. | Superlattices as materials.

Classification: LCC TA1573 .R64 2017 | DDC 681/.25 dc23 LC record available at <https://lcn.loc.gov/2017013783>

Published by

SPIE

P.O. Box 10

Bellingham, Washington 98227-0010 USA

Phone: +1 360.676.3290

Fax: +1 360.647.1445

Email: books@spie.org

Web: <http://spie.org>

Copyright © 2018 Society of Photo-Optical Instrumentation Engineers (SPIE)

All rights reserved. No part of this publication may be reproduced or distributed in any form or by any means without written permission of the publisher.

The content of this book reflects the work and thought of the authors. Every effort has been made to publish reliable and accurate information herein, but the publisher is not responsible for the validity of the information or for any outcomes resulting from reliance thereon.

Printed in the United States of America.

First Printing.

For updates to this book, visit <http://spie.org> and type “PM280” in the search field.

SPIE.

Contents

<i>Preface</i>	<i>ix</i>
<i>Acknowledgments</i>	<i>xiii</i>
Chapter 1. Infrared Detector Characterization	1
1.1 Introduction	1
1.2 Classification of Infrared Detectors	5
1.2.1 Photon detectors	5
1.2.2 Thermal detectors	10
1.3 Detector Figures of Merit	12
1.3.1 Responsivity	14
1.3.2 Noise equivalent power	14
1.3.3 Detectivity	14
1.3.4 Quantum efficiency	15
1.4 Fundamental Detector's Performance Limits	17
1.5 Performance of Focal Plane Arrays	21
1.5.1 Modulation transfer function	21
1.5.2 Noise equivalent difference temperature	22
1.5.3 Other issues	24
References	27
Chapter 2. Antimonide-based Materials	31
2.1 Bulk Materials	32
2.2 Epitaxial Layers	37
2.3 Physical Properties	42
2.4 Thermal Generation–Recombination Processes	52
References	57
Chapter 3. Type-II Superlattices	63
3.1 Bandgap-Engineered Infrared Detectors	65
3.2 Growth of Type-II Superlattices	67
3.3 Physical Properties	70
3.4 Carrier Lifetimes	76
3.5 InAs/GaSb versus InAs/InAsSb Superlattice Systems	81
References	83

Chapter 4. Antimonide-based Infrared Photodiodes	89
4.1 Recent Progress in Binary III-V Photodiodes	90
4.1.1 InSb photodiodes	90
4.1.2 InAs photodiodes	92
4.1.3 InAs avalanche photodiodes	94
4.2 InAsSb Bulk Photodiodes	97
4.2.1 Technology and properties	98
4.2.2 Performance limits	103
References	107
Chapter 5. Type-II Superlattice Infrared Photodiodes	111
5.1 InAs/GaSb Superlattice Photodiodes	112
5.1.1 MWIR photodiodes	113
5.1.2 LWIR photodiodes	119
5.2 InAs/InAsSb Superlattice Photodiodes	123
5.3 Device Passivation	126
5.4 Noise Mechanisms in Type-II Superlattice Photodetectors	130
References	135
Chapter 6. Infrared Barrier Photodetectors	141
6.1 Principle of Operation	141
6.2 SWIR Barrier Detectors	147
6.3 MWIR InAsSb Barrier Detectors	148
6.4 LWIR InAsSb Barrier Detectors	151
6.5 T2SL Barrier Detectors	152
6.6 Barrier Detectors versus HgCdTe Photodiodes	162
6.6.1 The $N_{dop} \times \tau_{diff}$ product as the figure of merit for diffusion-limited photodetectors	164
6.6.2 Dark current density	166
6.6.3 Noise equivalent difference temperature	171
6.6.4 Comparison with experimental data	172
6.7 Multicolor Barrier Detectors	176
References	179
Chapter 7. Cascade Infrared Photodetectors	185
7.1 Multistage Infrared Detectors	186
7.2 Type-II Superlattice Interband Cascade Infrared Detectors	188
7.2.1 Principle of operation	188
7.2.2 MWIR interband cascade detectors	190
7.2.3 LWIR interband cascade detectors	194
7.3 Performance Comparison with HgCdTe HOT Photodetectors	196
References	199

Chapter 8. Coupling of Infrared Radiation with Detector	203
8.1 Standard Coupling	203
8.2 Plasmonic Coupling	206
8.2.1 Surface plasmons	207
8.2.2 Plasmonic coupling of infrared detectors	211
8.3 Photon Trapping Detectors	217
References	223
Chapter 9. Focal Plane Arrays	227
9.1 Trends in Infrared Focal Plane Arrays	227
9.2 Infrared FPA Considerations	231
9.3 InSb Arrays	238
9.4 InAsSb nBn Detector FPAs	242
9.5 Type-II Superlattice FPAs	245
References	253
Chapter 10. Final Remarks	259
10.1 P-on-n HgCdTe Photodiodes	260
10.2 Manufacturability of Focal Plane Arrays	262
10.3 Conclusions	265
References	267
<i>Index</i>	269

Preface

Among the many materials investigated in the infrared (IR) field, narrow-gap semiconductors are the most important in the IR photon detector family. Although the first widely used narrow-gap materials were lead salts (during the 1950s, IR detectors were built using single-element-cooled PbS and PbSe photoconductive detectors, primarily for anti-missile seekers), this semiconductor family was not well distinguished. This situation seems to have resulted from two reasons: the preparation process of lead salt photoconductive polycrystalline detectors was not well understood and could only be reproduced with well-tried recipes; and the theory of narrow-gap semiconductor bandgap structure was not well known for correct interpretation of the measured transport and photoelectrical properties of these materials.

The discovery of the transistor stimulated a considerable improvement in the growth and material purification techniques. At the same time, rapid advances were being made in the newly discovered III-V compound semiconductor family. One such material was InSb from which the first practical photovoltaic detector was fabricated in 1955 [G. R. Mitchell, A. E. Goldberg, and S. W. Kurnick, *Phys. Rev.* **97**, 239 (1955)]. In 1957, P. W. Kane [*J. Phys. Chem. Solids* **1**, 249 (1957)] using a method of quantum perturbation theory (the so-called **k·p** method), correctly described the band structure of InSb. Since that time, the Kane band model has been of considerable importance for narrow-gap semiconductor materials.

The end of the 1950s saw the introduction of narrow-gap semiconductor alloys in III-V (InAsSb), IV-VI (PbSnTe, PbSnSe), and II-VI (HgCdTe) material systems. These alloys allowed the bandgap of the semiconductor and hence the spectral response of the detector to be custom tailored for specific applications. Discovery of variable bandgap $\text{Hg}_{1-x}\text{Cd}_x\text{Te}$ (HgCdTe) ternary alloy in 1959 by Lawson and co-workers [*J. Phys. Chem. Solids* **9**, 325 (1959)] triggered an unprecedented degree of freedom in infrared detector design. Over the next five decades, this material system successfully fought off major challenges from different material systems, but despite that, it has more competitors today than ever before. It is interesting, however, that none of these competitors can compete in terms of fundamental properties. They may promise to be more manufacturable, but never to

provide higher performance or, with the exception of thermal detectors, to operate at higher temperature.

Recently, there has been considerable progress towards III-V antimonide-based, low-dimensional solids development, and device design innovations. Their development results from two primary motivations: the perceived challenges of reproducibly fabricating high-operability HgCdTe focal plane arrays (FPAs) at reasonable cost and theoretical predictions of lower Auger recombination for type-II superlattice (T2SL) detectors compared to HgCdTe. Lower Auger recombination translates into a fundamental advantage for T2SL over HgCdTe in terms of lower dark current and/or higher operating temperature provided other parameters such as Shockley–Read–Hall lifetimes are equal.

In fact, investigations of antimonide-based materials began at about the same time as HgCdTe—in the 1950s, and the apparent rapid success of their technology, especially low-dimensional solids, depends on the previous five decades of III-V materials and device research. However, the sophisticated physics associated with the antimonide-based bandgap engineering concept started at the beginning of the 1990s gave a new impact and interest in development of infrared detector structures within academic and national laboratories. In addition, implementation of barriers in photoconductor structures, in so-called barrier detectors, prevents current flow in the majority carrier band of a detector's absorber but allows unimpeded flow in the minority carrier band. As a result, this concept resurrects the performance of antimonide-based focal plane arrays and gives a new perspective in their applications. A new emerging strategy includes antimonide-based T2SLs, barrier structures such as the nBn detector with lower generation-recombination leakage mechanisms, photon trapping detectors, and multi-stage/cascade infrared devices.

This book describes the present status of new concepts of antimonide-based infrared detectors. The intent is to focus on designs having the largest impact on the mainstream of infrared detector technologies today. A secondary aim is to outline the evolution of detector technologies showing why certain device designs and architectures have emerged recently as alternative technologies to the HgCdTe ternary alloy. The third goal is to emphasize the applicability of detectors in the design of FPAs. This is especially addressed to the InAsSb ternary alloys system and T2SL materials. It seems to be clear that some of these solutions have emerged as real competitors of HgCdTe photodetectors. Special efforts are directed on the physical limits of detector performance and the performance comparison of antimonide-based detectors with the current stage of HgCdTe photodiodes. The reader should gain a good understanding of the similarities and contrasts and the strengths and weaknesses of a multitude of approaches that have been developed over two last decades as an effort to improve our ability to sense infrared radiation.

The level of this book is suitable for graduate students in physics and engineering who have received preparation in modern solid-state physics and electronic circuits. This book will be of interest to individuals working with aerospace sensors and systems, remote sensing, thermal imaging, military imaging, optical telecommunications, infrared spectroscopy, and lidar, as well. To satisfy all these needs, each chapter first discusses the principles needed to understand the chapter topic as well as some historical background before presenting the reader with the most recent information available. For those currently in the field, this book can be used as a collection of useful data, as a guide to literature in the field, and as an overview of topics in the field. The book also could be used as a reference for participants of educational short courses, such as those organized by SPIE.

The book is divided into ten chapters. The introduction (Chapter 1) gives a short historical overview of the development of IR detectors with antimonide-based materials and describes the detector classification and figures of merit of infrared detectors. The main topics in crystal growth technology, both bulk materials and epitaxial layers, as well their physical properties are given in Chapter 2. Special emphasis is paid to the modern epitaxy technologies such as molecular beam epitaxy and metalorganic chemical vapor deposition. Chapter 3 provides similar information about type-II superlattices. The next two chapters concern technology and performance of both bulk as well as superlattice antimonide-based infrared detectors. New classes of infrared detectors called barrier detectors, trapping detectors, and cascade detectors are covered in three succeeding chapters: Chapters 6, 7, and 8. An overview of antimonide-based FPA architectures is given in Chapter 9. Finally, remarks are included in the last chapter.

Antoni Rogalski
Małgorzata Kopytko
Piotr Martyniuk
March 2018

Acknowledgments

In the course of writing this book, many people have assisted us and offered their support. We would like, first, to express appreciation to the management of the Institute of Applied Physics, Military University of Technology, for providing the environment in which we worked on the book. The writing of the book has been partially done under financial support of the Polish Ministry of Sciences and Higher Education, The National Science Centre (Poland) - (Grant nos. 2015/17/B/ST5/01753 and 2015/19/B/ST7/02200) and The National Centre for Research and Development (Poland) - (Grant no. POIR.04.01.04-00-0027/16-00).

The authors have benefited from the kind cooperation of many scientists who are actively working in infrared detector technologies. The preparation of this book was aided by many informative and stimulating discussions that the authors had with their colleagues at the Institute of Applied Physics, Military University of Technology in Warsaw. The authors thank the following individuals for providing preprints, unpublished information, and in some cases original figures, which are used in preparing the book: Dr. M.A. Kinch (DRS Infrared Technologies, Dallas), Drs. S.D. Gunapala and D.Z.-Y. Ting (California Institute of Technology, Pasadena), Dr. M. Kimata (Ritsumeikan University, Shiga), Dr. M. Razeghi (Northwestern University, Evanston), Drs. M.Z. Tidrow and P. Norton (U.S. Army RDECOM CERDEC NVESD, Ft. Belvoir), Dr. S. Krishna (University of New Mexico, Albuquerque), and Prof. J. Piotrowski (Vigo System Ltd., Ożarów Mazowiecki). Thanks also to SPIE Press, especially Ms. Nicole Harris, for her cooperation and care in publishing this edition.